

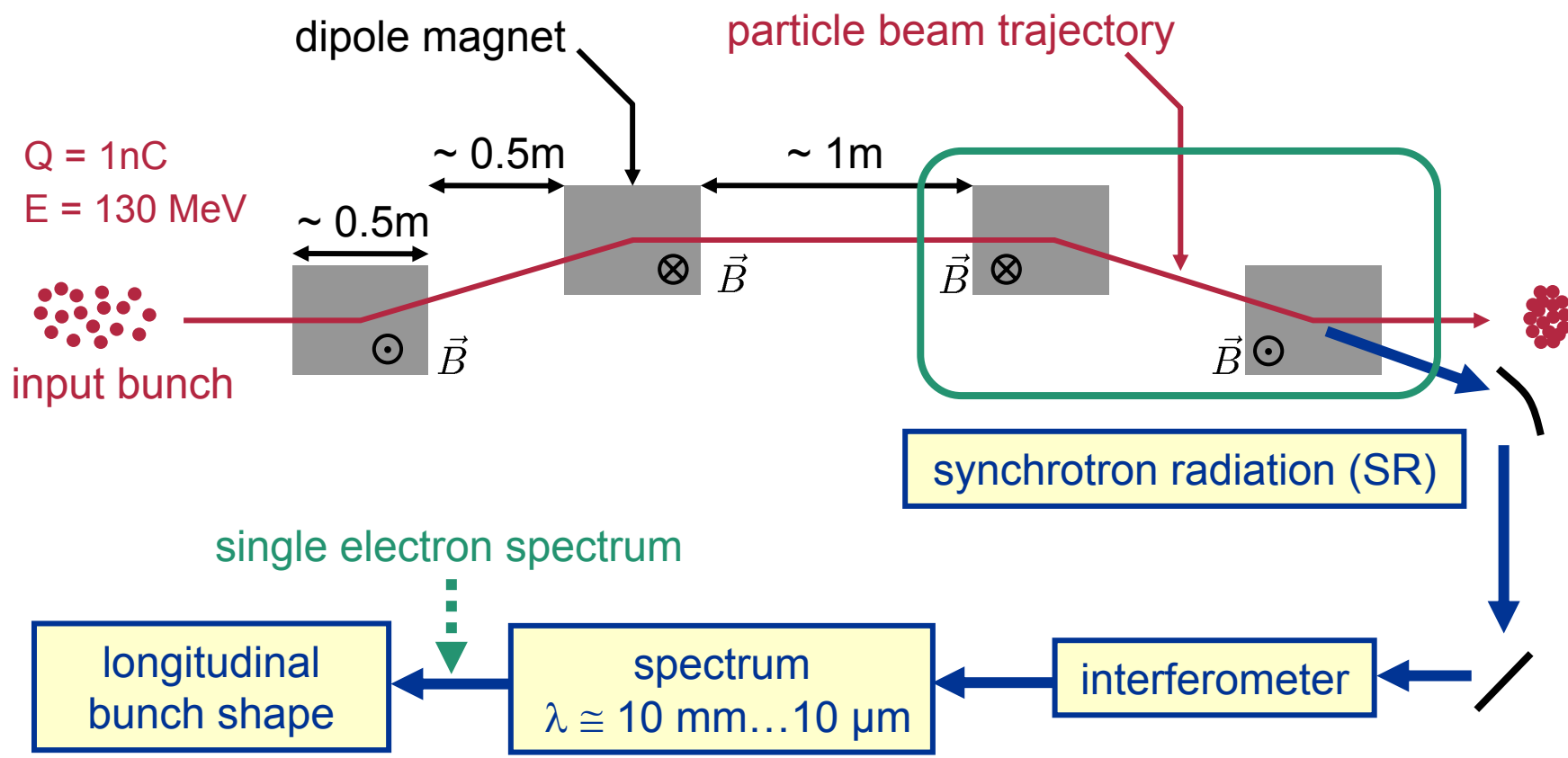
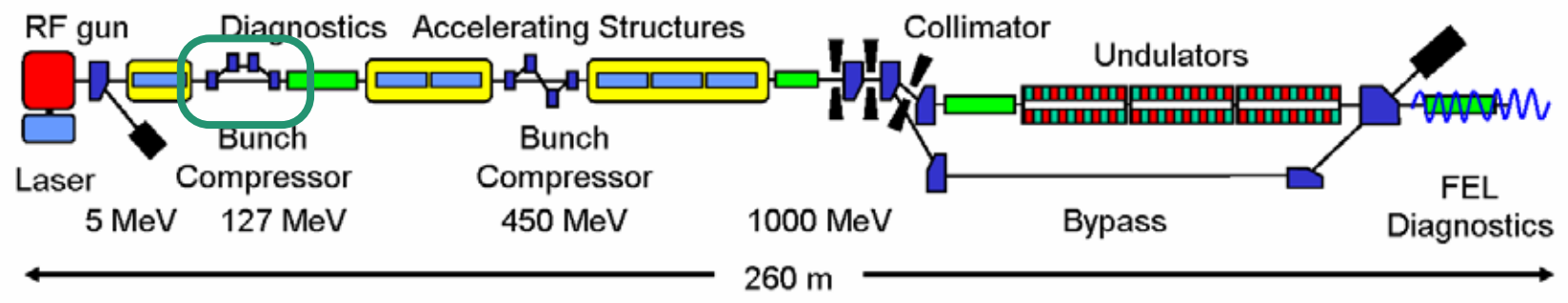
# Investigation of the Side Wall Influence on Synchrotron Radiation Generated at the First Bunch Compressor of FLASH by Numerical Simulation

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08.10.2007, DESY Hamburg

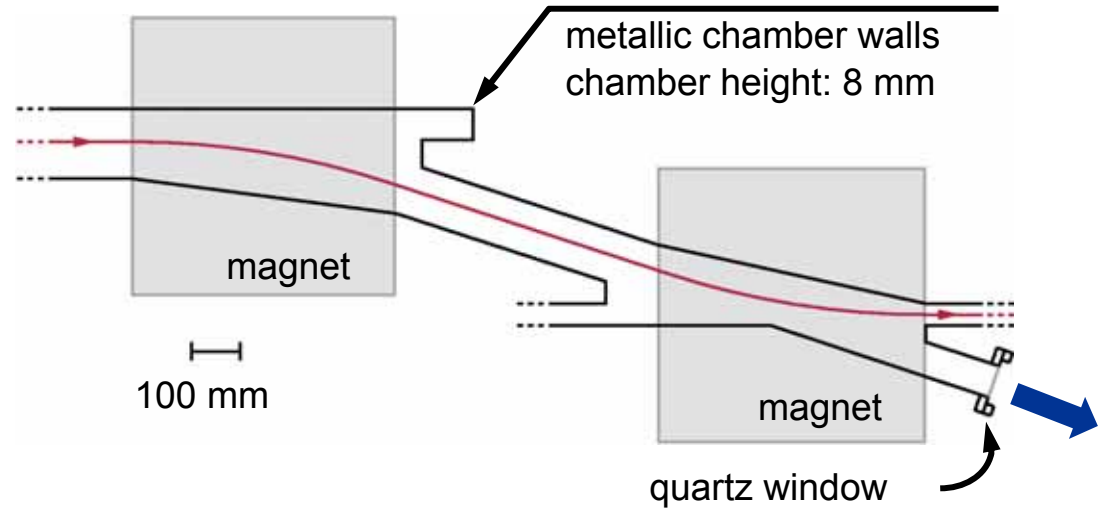
Technische Universität Darmstadt, Fachbereich Elektrotechnik und Informationstechnik  
Schlossgartenstr. 8, 64289 Darmstadt, Germany - URL: [www.TEMF.de](http://www.TEMF.de)

# Introduction: Synchrotron Radiation Bunch Diagnostics at DESY





## vacuum chamber



**what is the influence of the chamber (side walls) on the spectrum?**



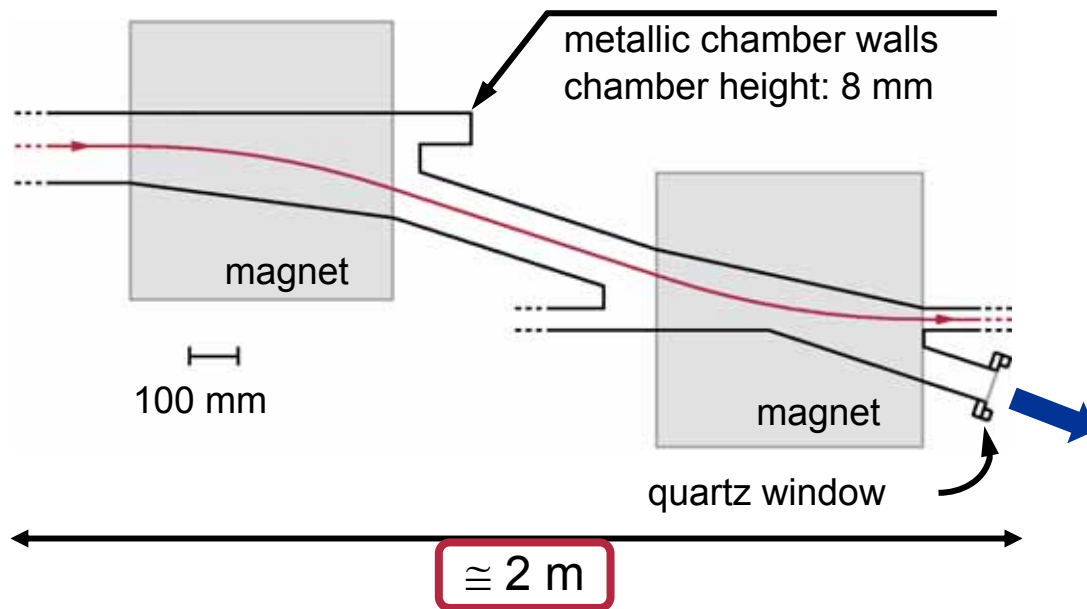
**numerical calculation?**

- Simulation Methods
- 2D Field Distribution Examples Inside the Chamber
- Influence of Side Walls (Intensity-Comparison)
- Comparison Simulation - Measurements
- Influence of Side Walls (Intensity Patterns)
- Influence of Transversal Bunch Shape

# Simulation Methods

## main simulation challenges for EM field calculation

- very high frequency problem
- broad frequency range

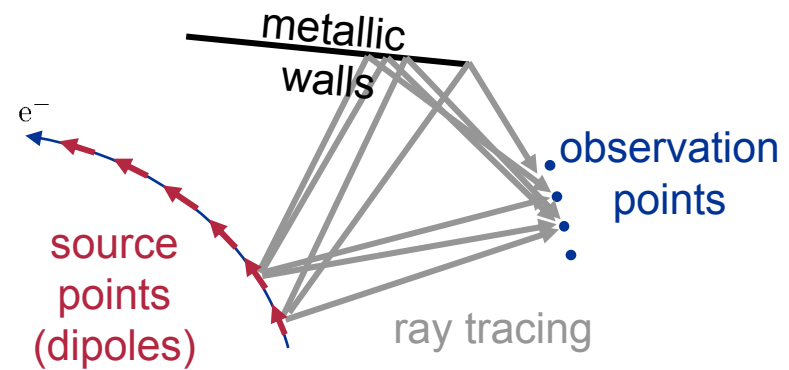
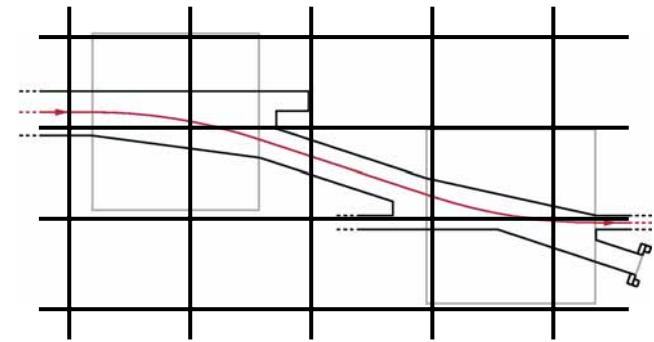


$$Q = 1 \text{ nC}$$

$$E = 130 \text{ MeV}$$

$$\lambda = 10 \text{ mm} \dots 10 \mu\text{m}$$

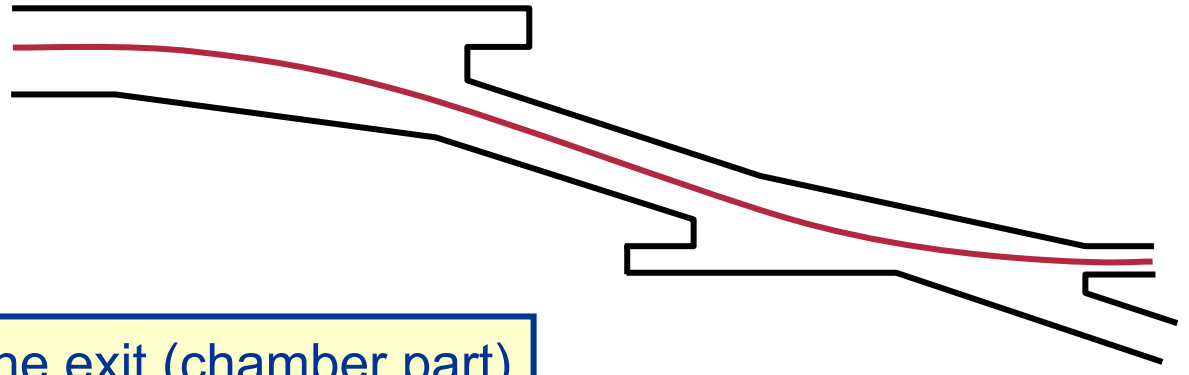
- discretizing methods (FIT)
  - high memory consumption
  - dispersion error problems
  - 2D-Implementation
- asymptotic methods - UTD (geometrical optics based)
  - no discretization of structure but of source and monitor points
  - raytracing complex
  - accuracy limit
  - different formulations and models tested
- Fourier optics
  - radiation from waveguide exit
- point charge (single electron spectrum)



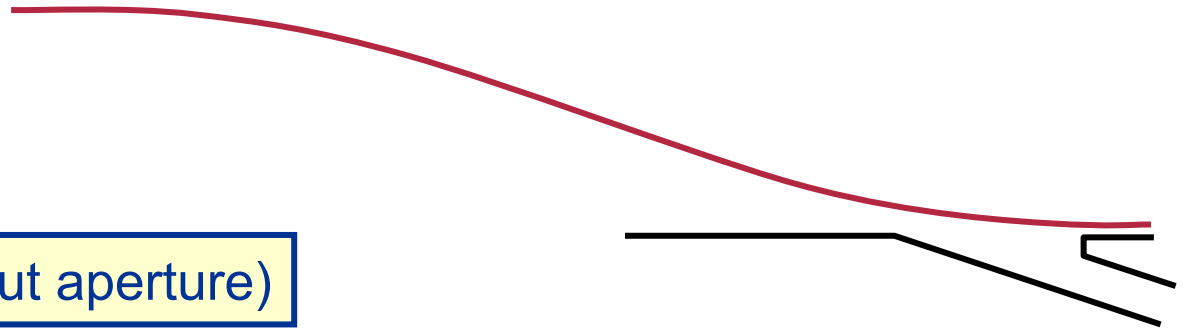




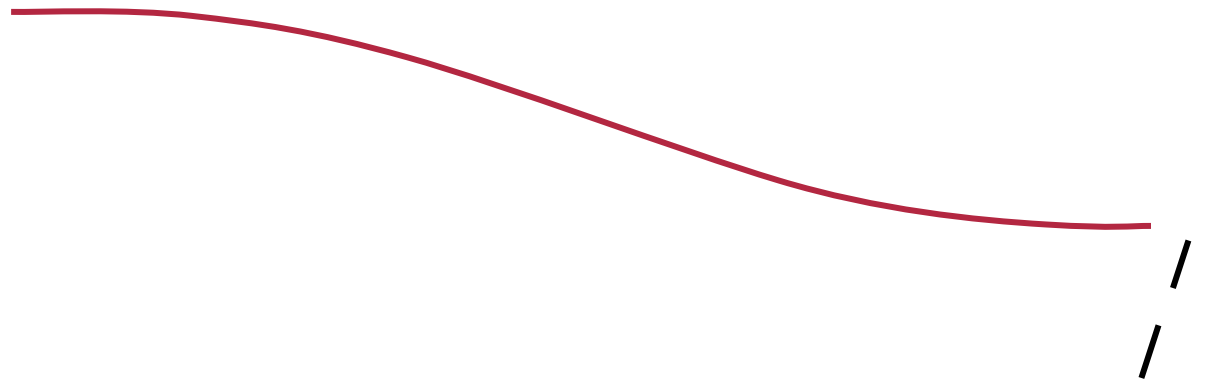
all walls



only the walls near the exit (chamber part)



without side walls (but aperture)

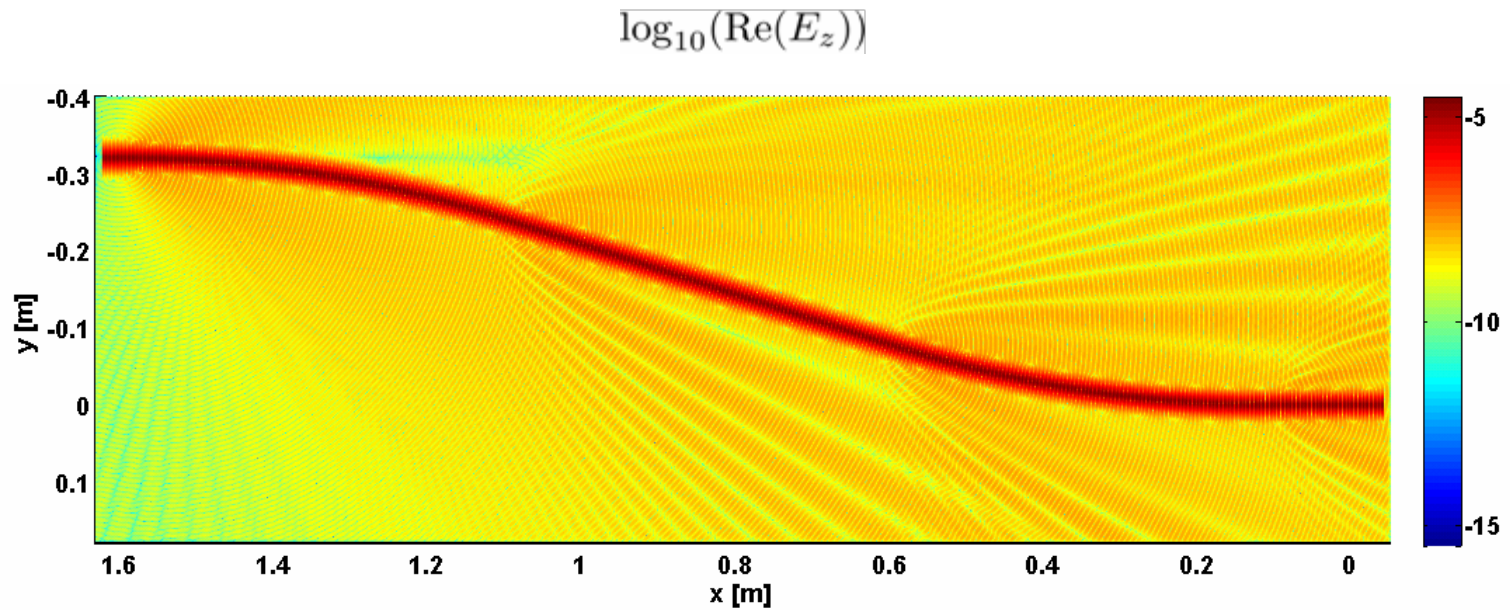


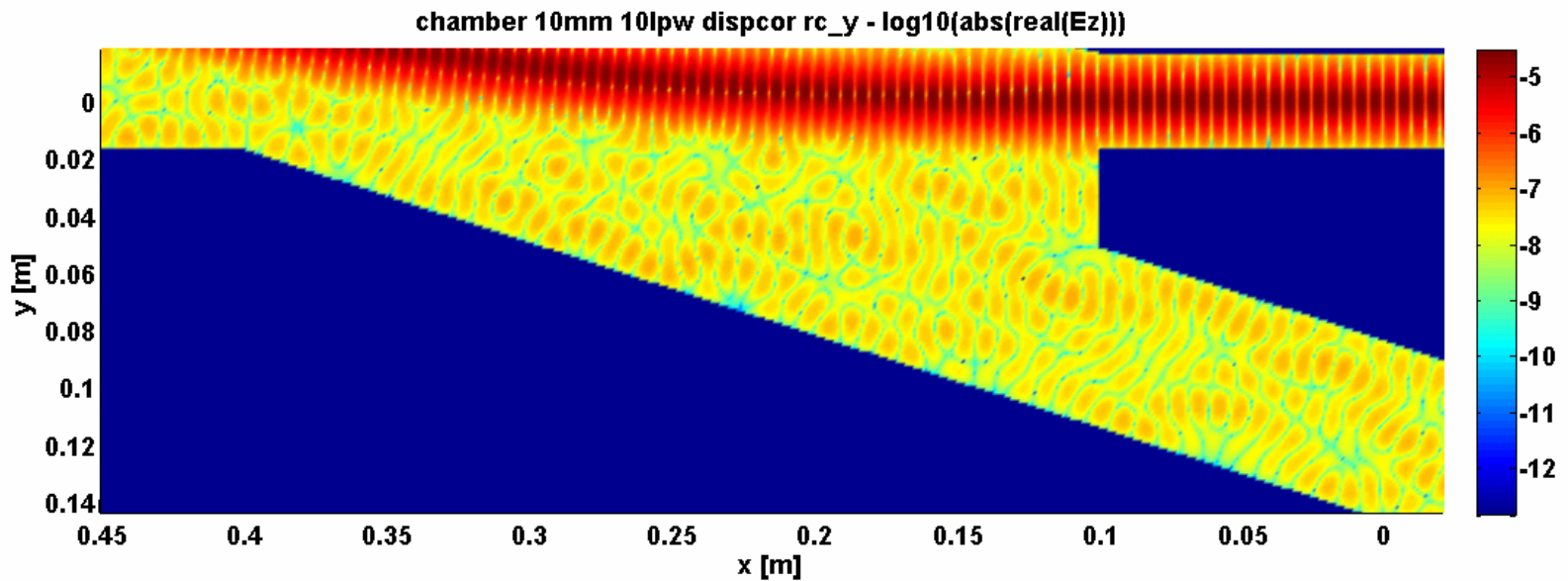
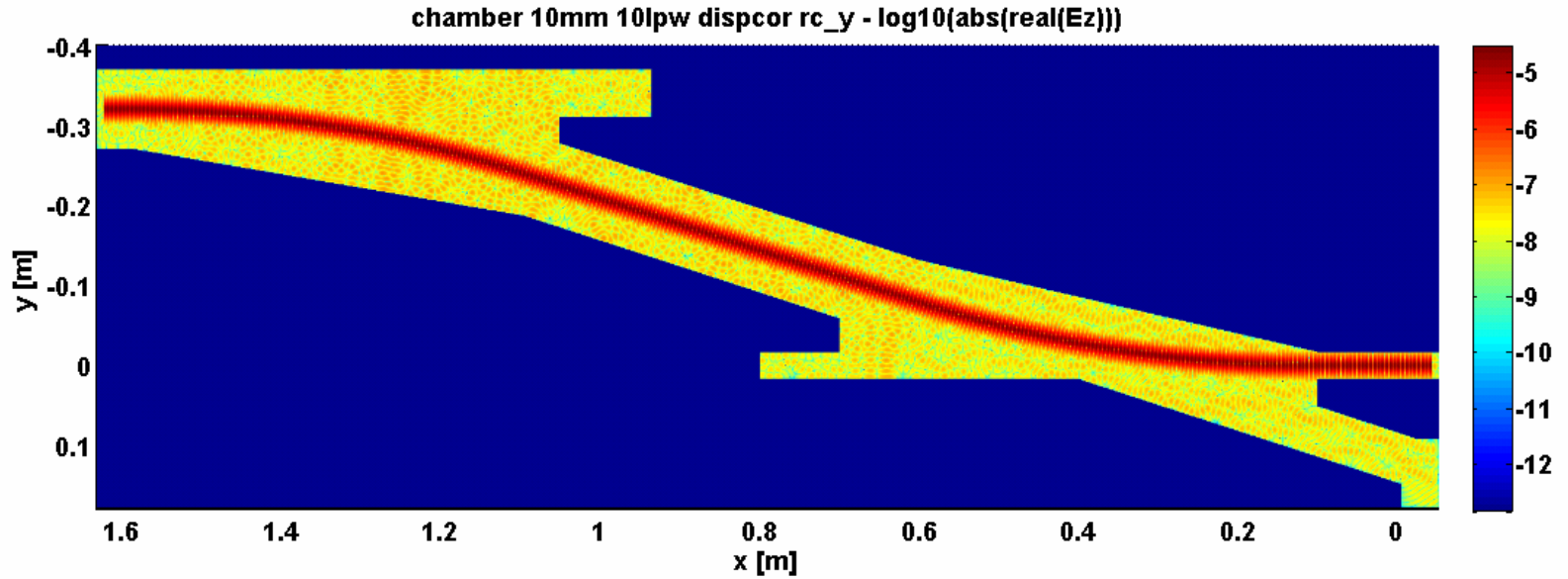
- FIT:
  - results better than expected
  - only for long wavelengths:  $\lambda > 2.5\text{mm}$  (5mm)
- optics:
  - good results for simple wall model
  - difficult to apply (many parameters, accuracy, runtime)
  - no universal method (wavelength and model dependent)
  - problematic for model with all walls
- Fourier optics after chamber exit
  - in general good results and efficient
  - resolution problems at 10um
- estimated accuracy (spectrum): ~1%..20%  
depending on wavelength, used method and model

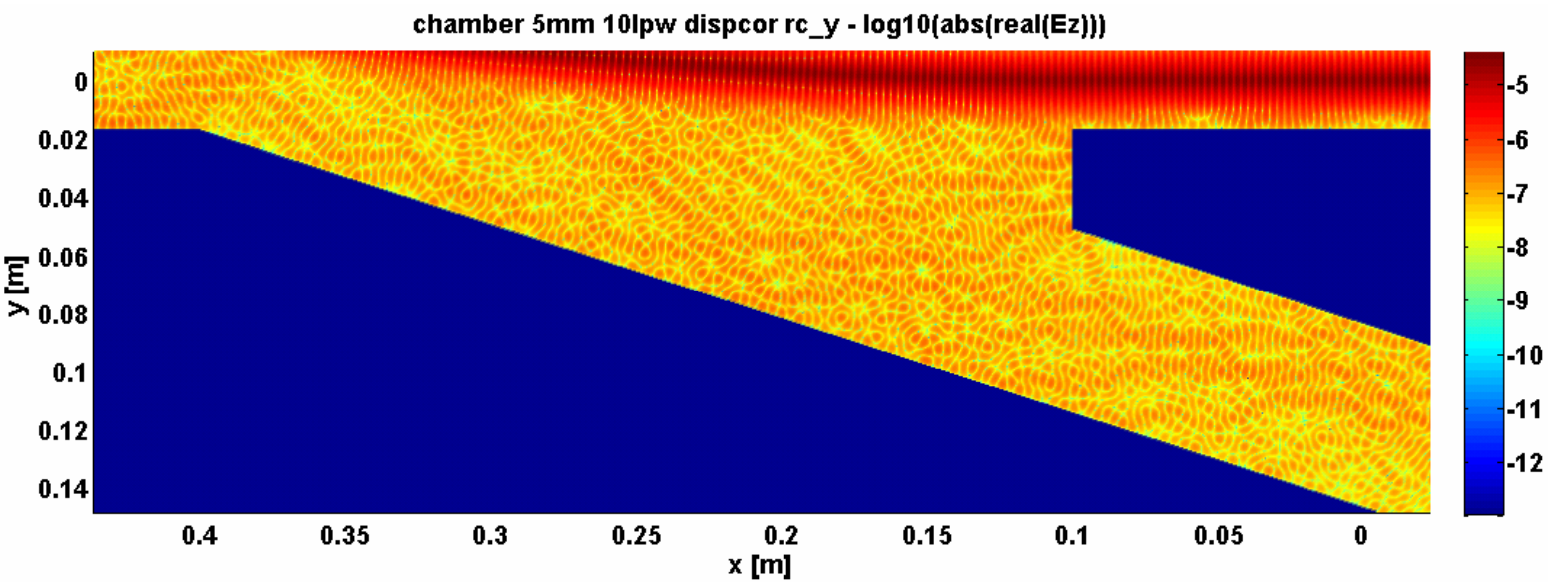
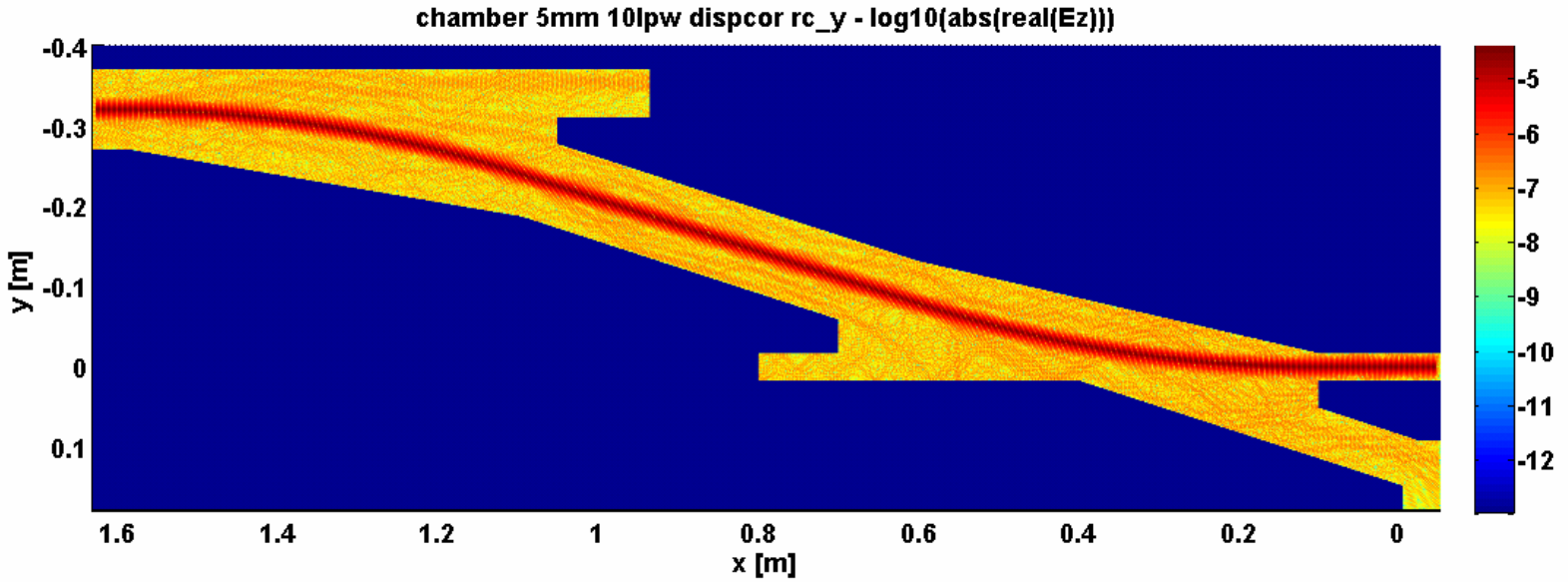
# 2D Field Distribution Examples Inside the Chamber (FIT)

## modell without side walls

$\lambda = 10\text{mm}$ , mode 2

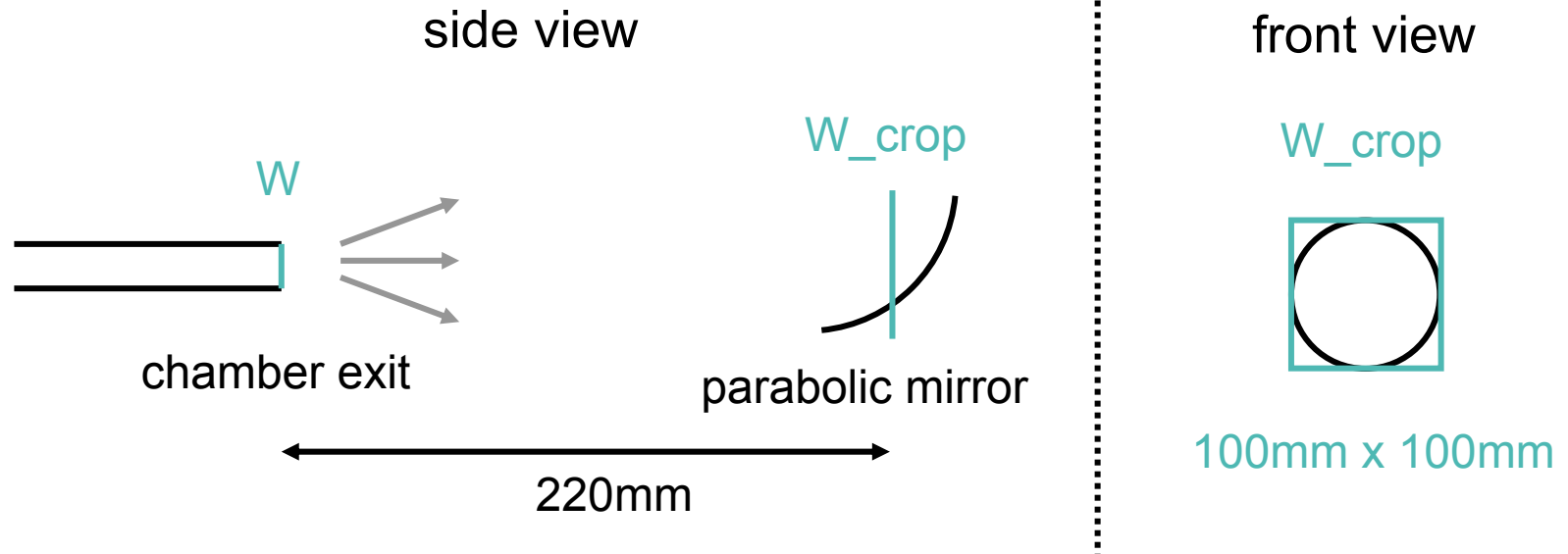






# Influence of Side Walls: Intensity-Comparison

## radiated energy

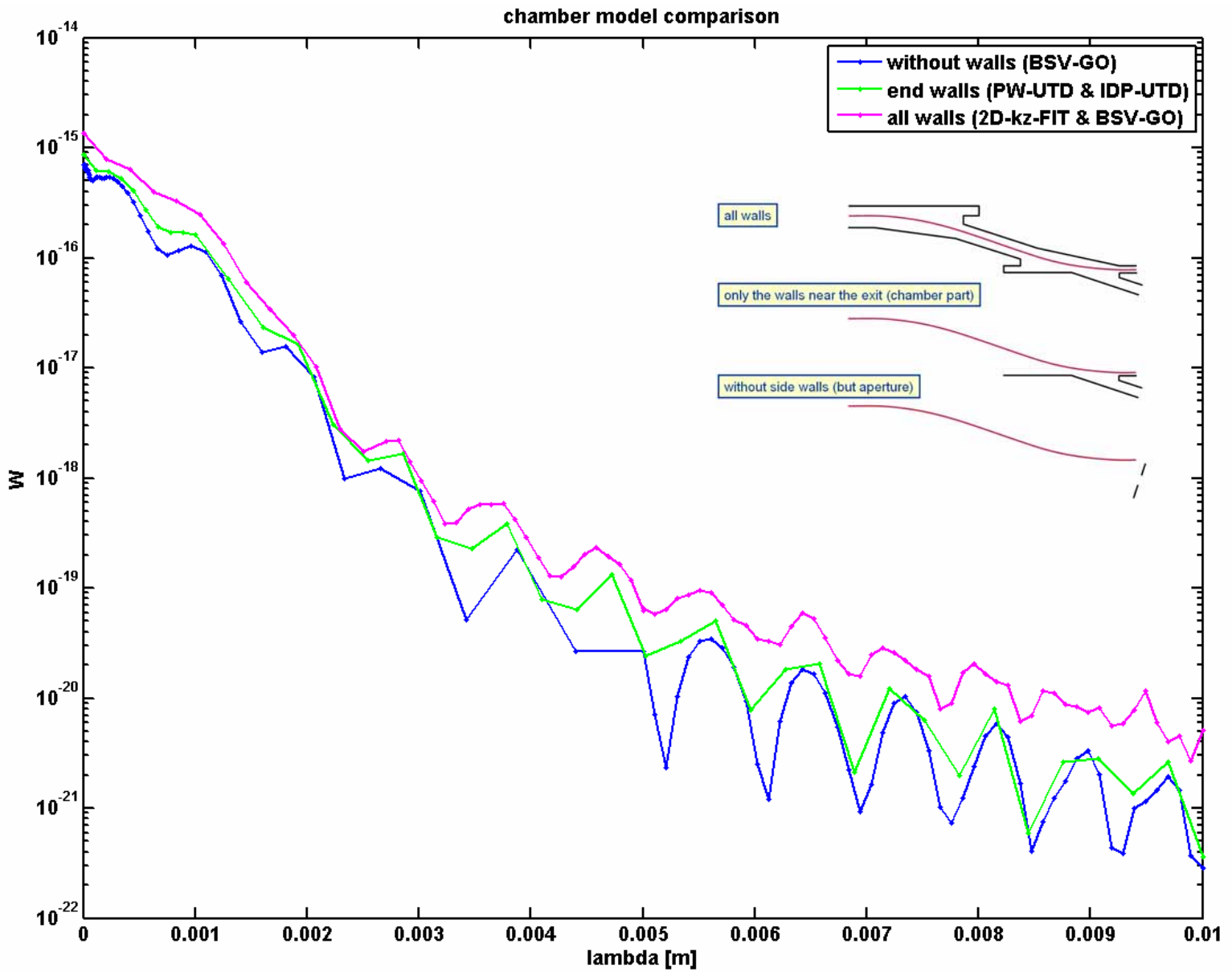


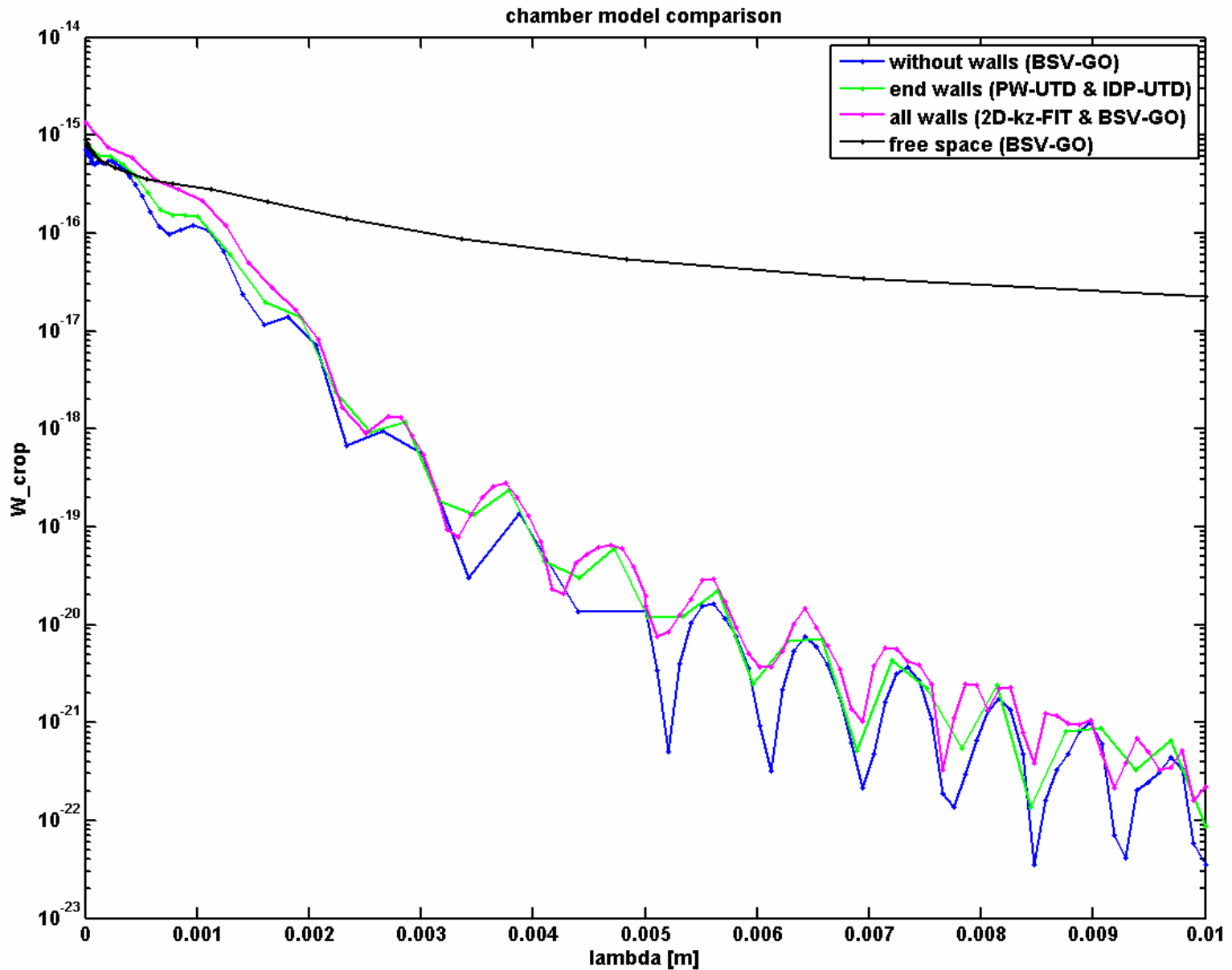
$W$ : though waveguide exit  
 $W_{crop}$ : rectangular area at paraboloid

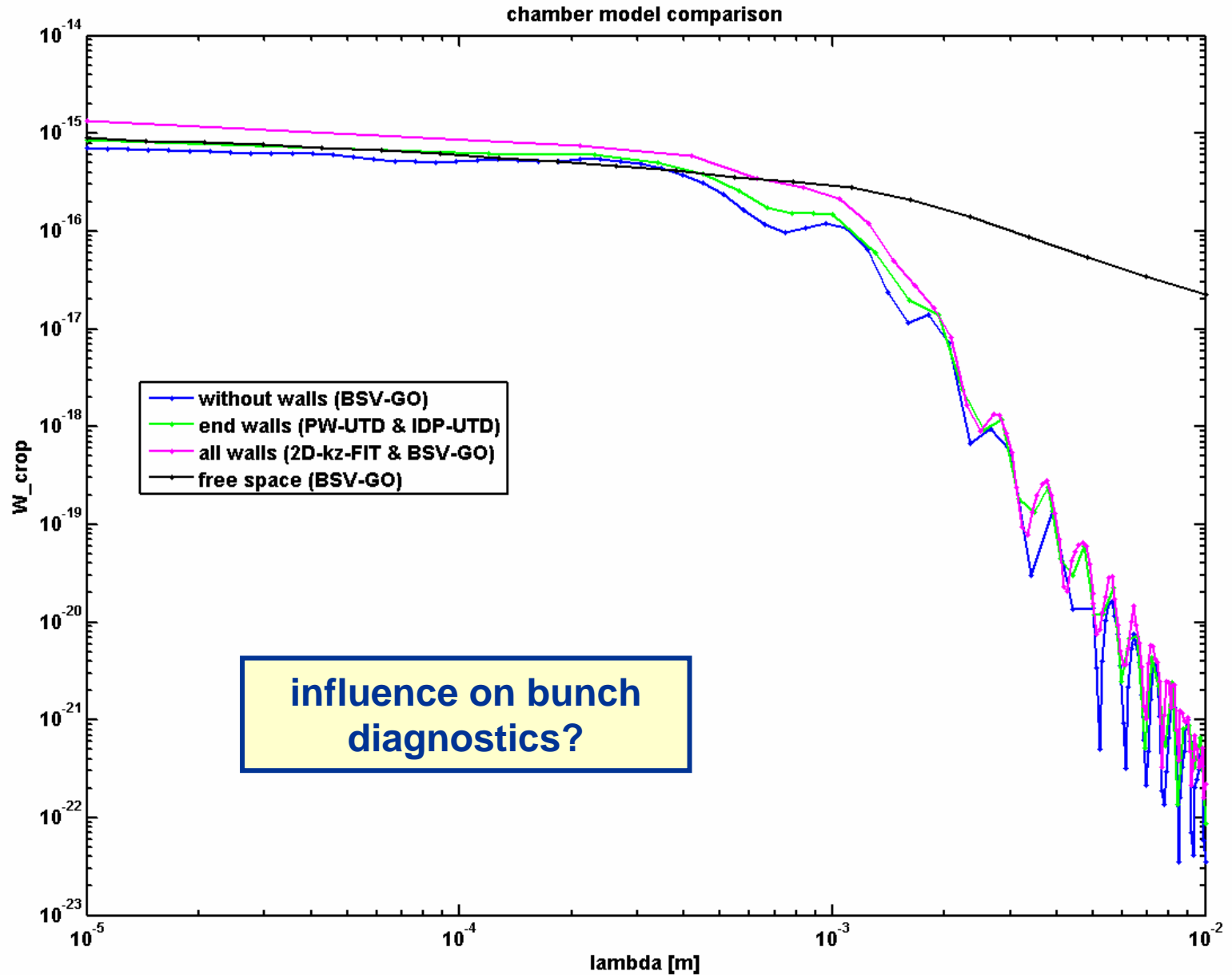
$[W] = J/Hz$





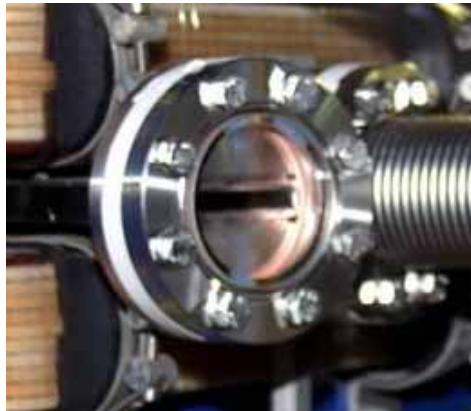




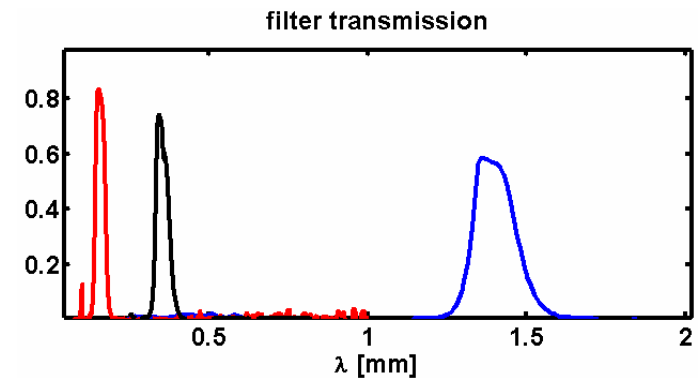


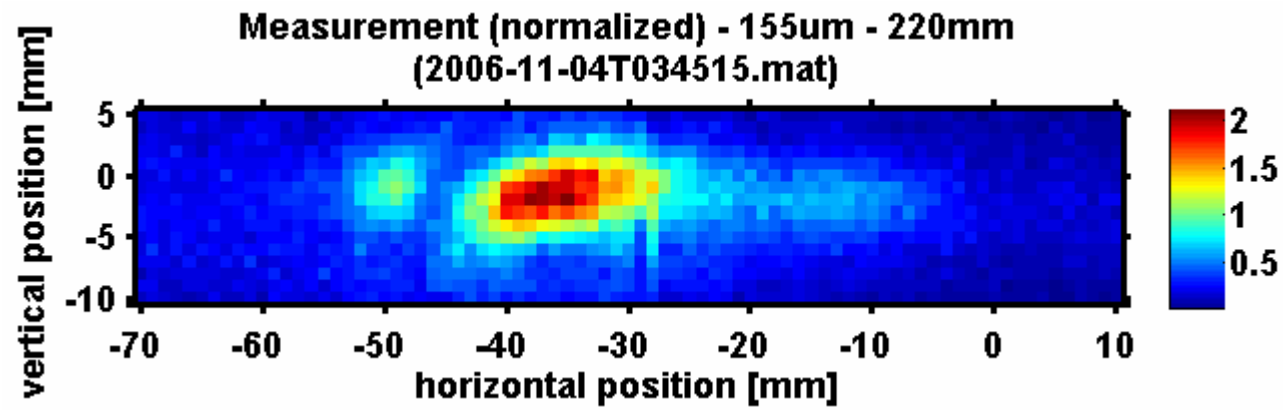
# Comparison Simulation - Measurement

- fields in front of waveguide exit
  - 220 mm distance (parabolic mirror position)
  - 2D transversal scan



- 3 frequencies
- pyroelectric detector
- Simulation:
  - point charge
  - considering filter characteristic (10 frequency samples)
  - Poynting vector

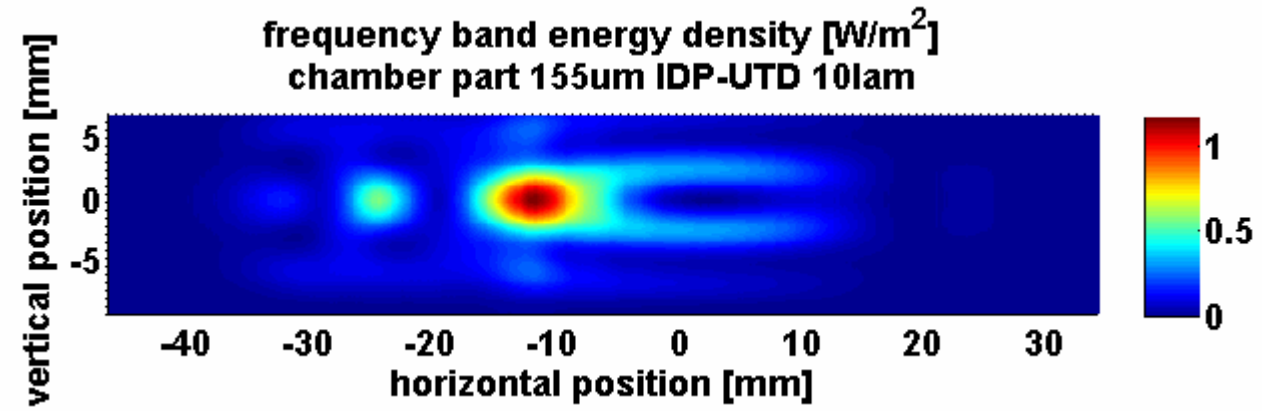


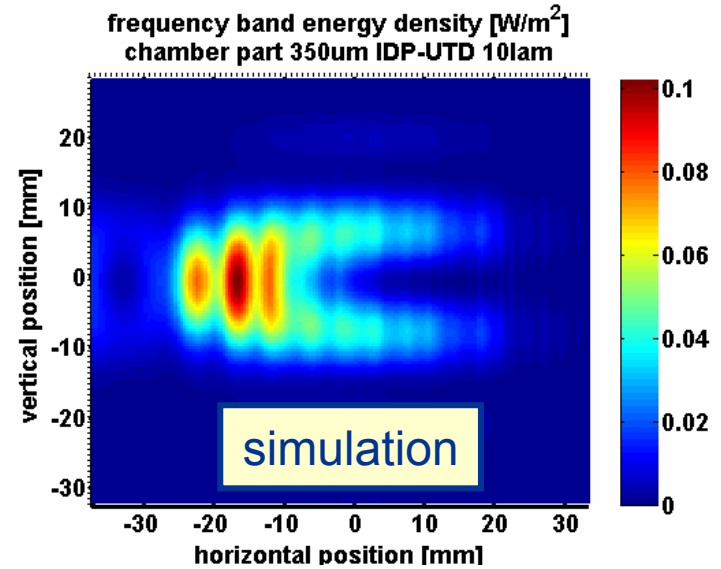
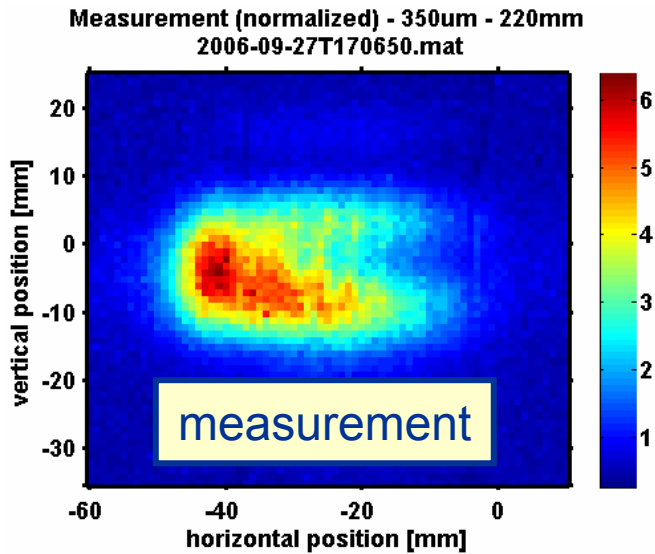


measurement

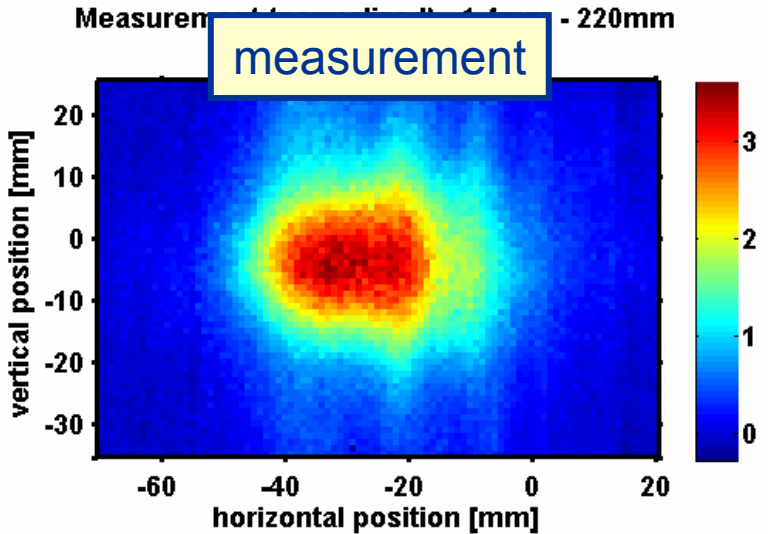
good agreement

simulation



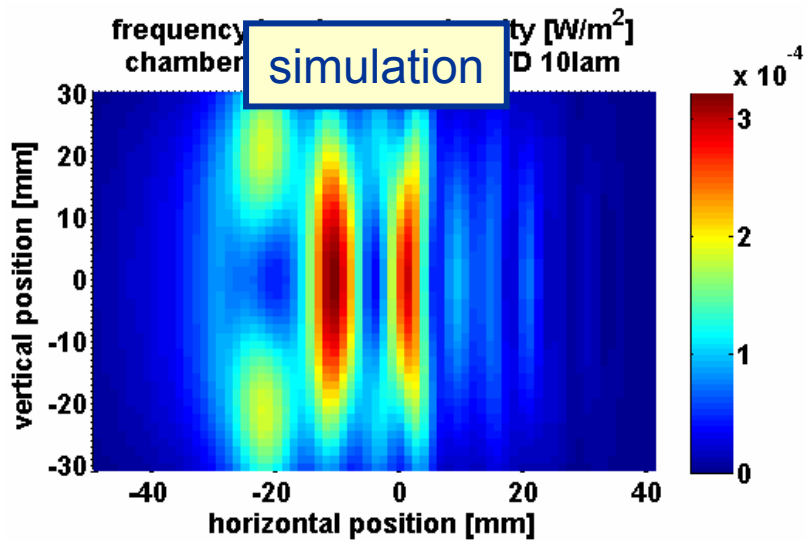


good agreement  
except interference pattern not visible



unexplained differences

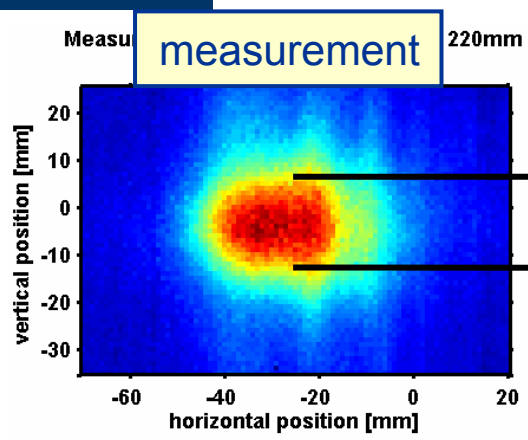
no errors in simulation detected



problems with measurement?

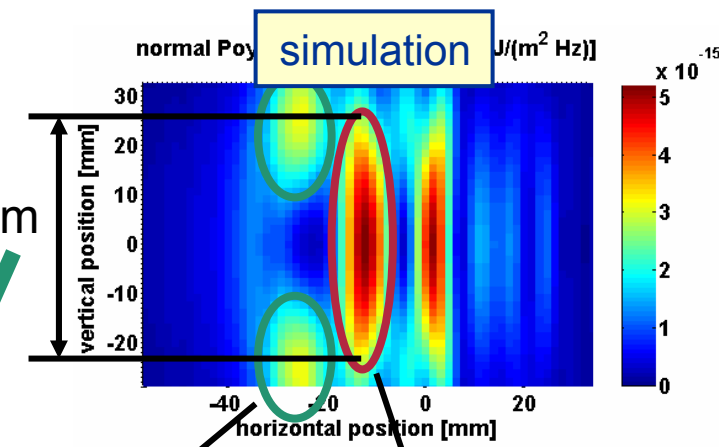
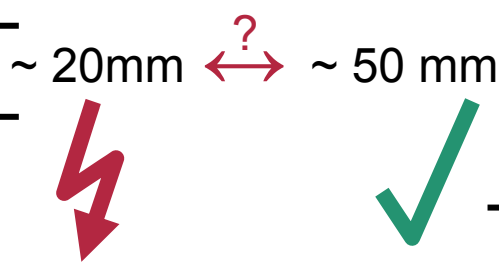


# Plausibility of 1.4mm Meas.



spot size:

FWHM



$\cong \text{TM}_{01}$ -mode  $\cong \text{TE}_{01}$ -mode

analytic intensity at 220mm for uniformly illuminated 8mm slit:

$$I \propto \left( \frac{\sin\left(\frac{\pi Dx}{\lambda L}\right)}{\frac{\pi Dx}{\lambda L}} \right)^2$$

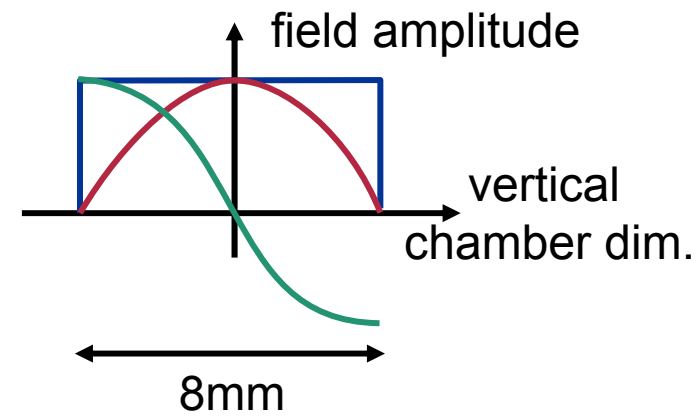
FWHM = 34mm

= minimum FWHM

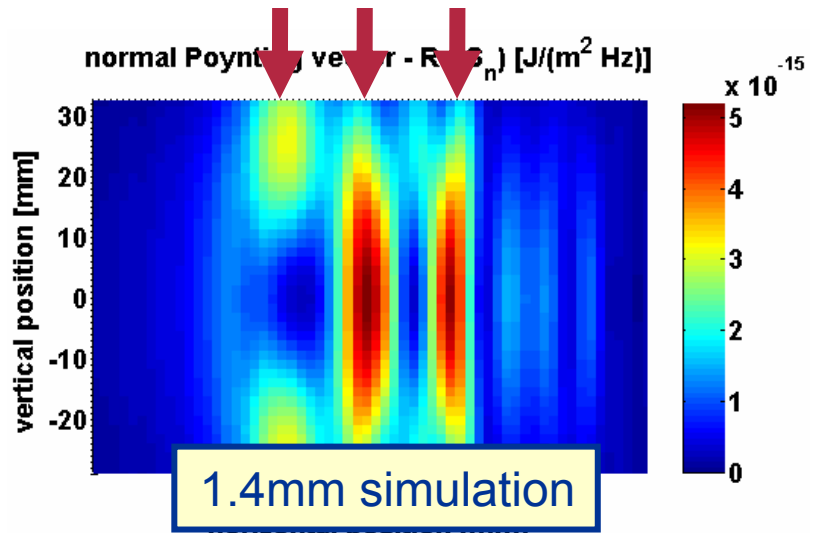
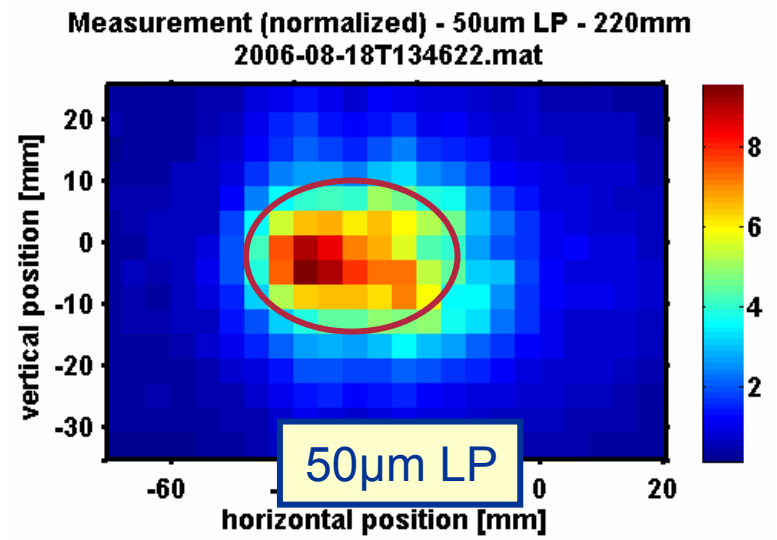
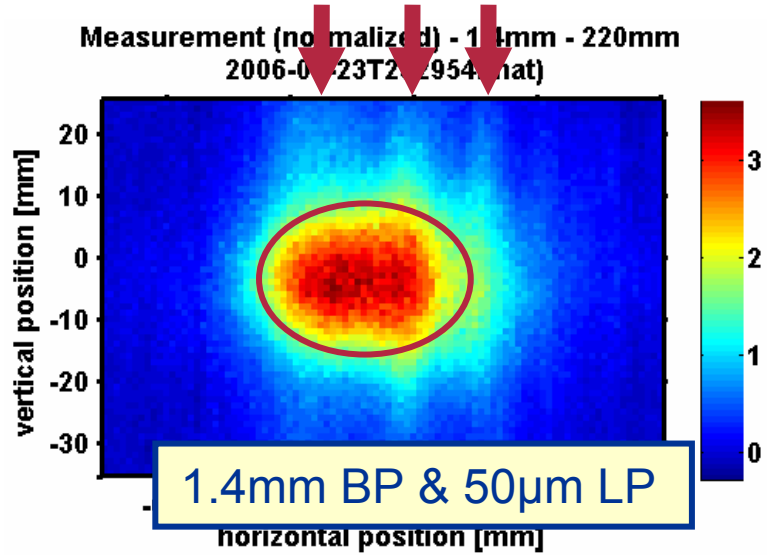
( $I \cong$  Fourier trf. of slit field)

$\text{FWHM}_{\text{measurement}} < \text{FWHM}_{\text{uniform}} !$

$$\text{FWHM}_{\text{uniform}} < \text{FWHM}_{\text{TE01}} < \text{FWHM}_{\text{TM01}}$$

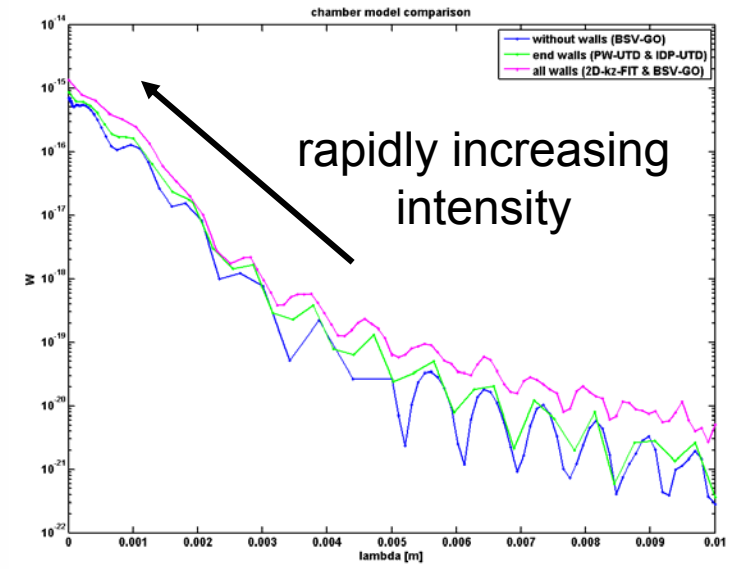
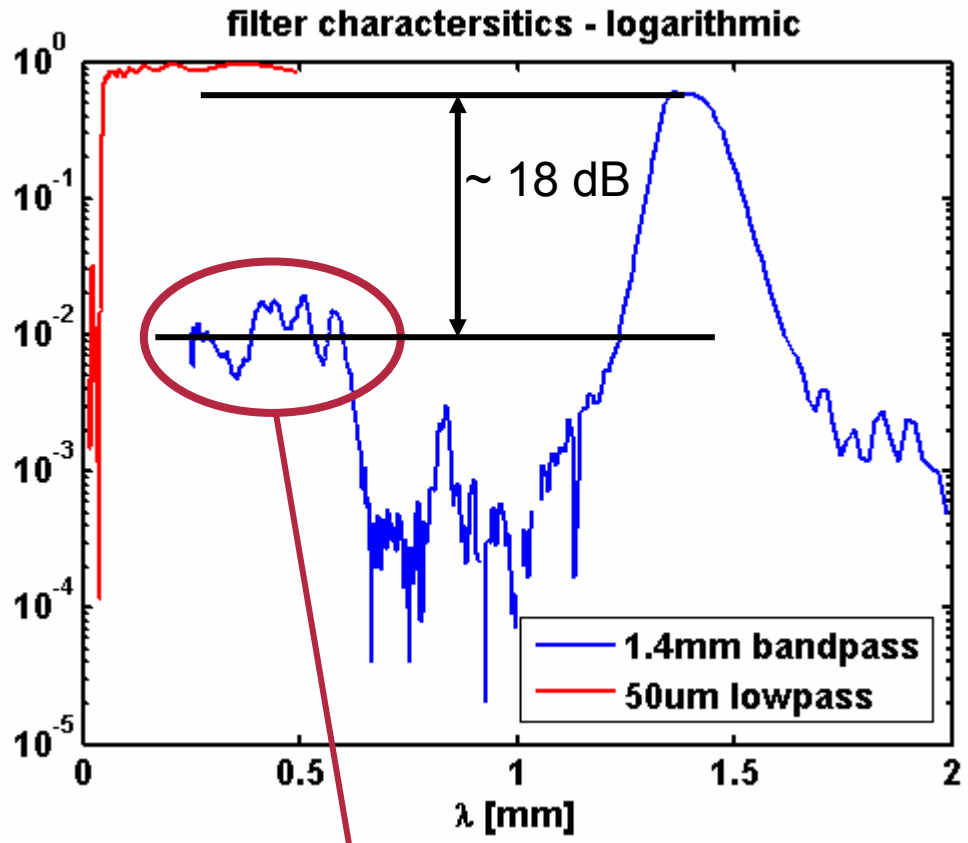


**inconsistency in measurement**



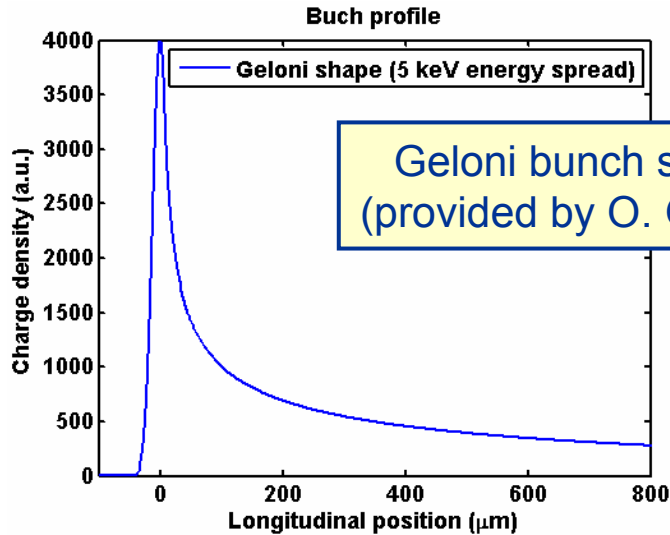
no significant change in measurement pattern when 1.4mm BP added

pattern from simulation slightly seen in measurement



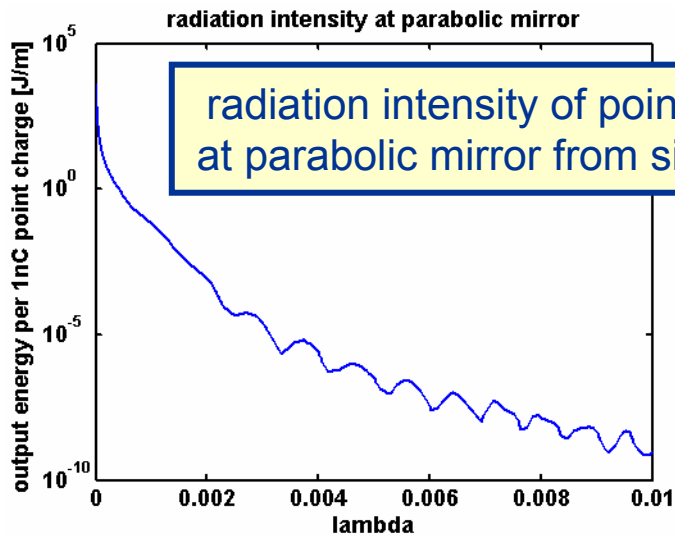
high intensity short wavelength radiation  
+ imperfect filter characteristic  
→ 1.4mm signal “overshadowed” ?

more detailed estimation with

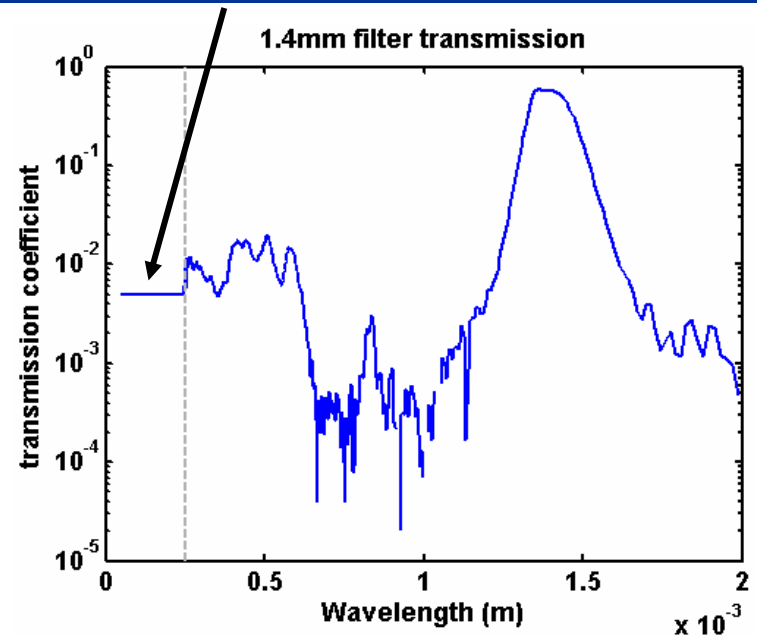


Geloni bunch shape  
(provided by O. Grimm)

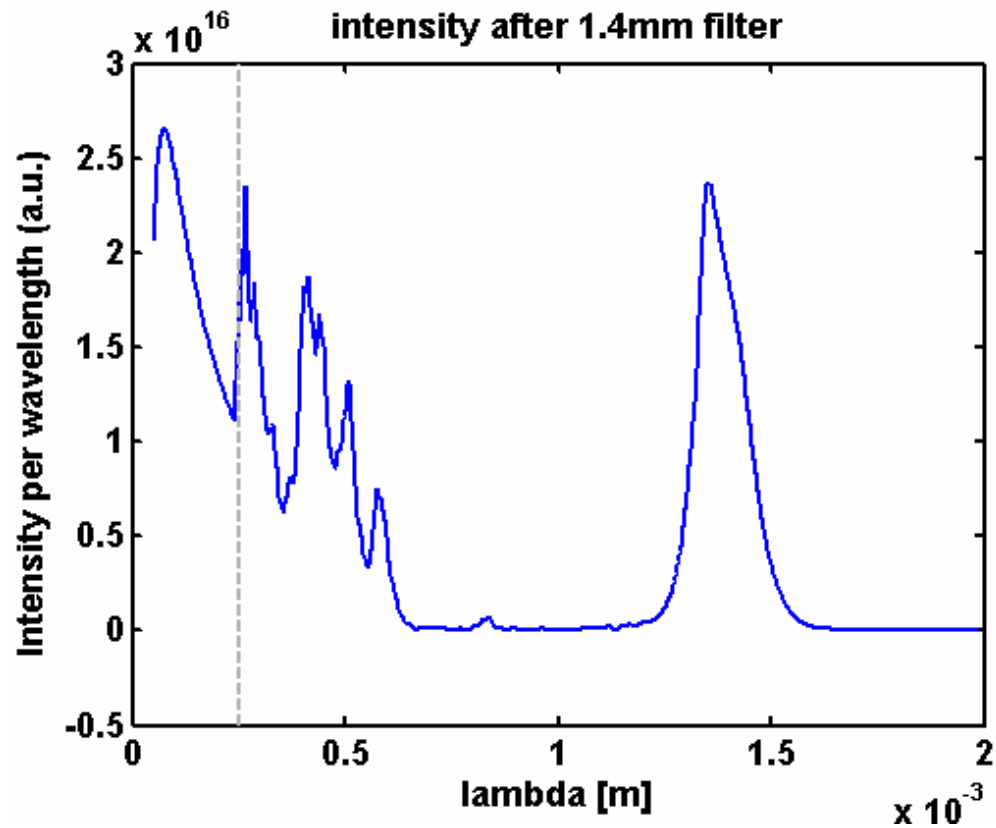
1.4mm BP filter transmission (250 $\mu\text{m}$ ..2mm)  
with extrapolation (50 $\mu\text{m}$ ..250 $\mu\text{m}$ )



radiation intensity of point charge  
at parabolic mirror from simulation



# 1.4mm Geloni Estimation



integrated intensity (a.u.):



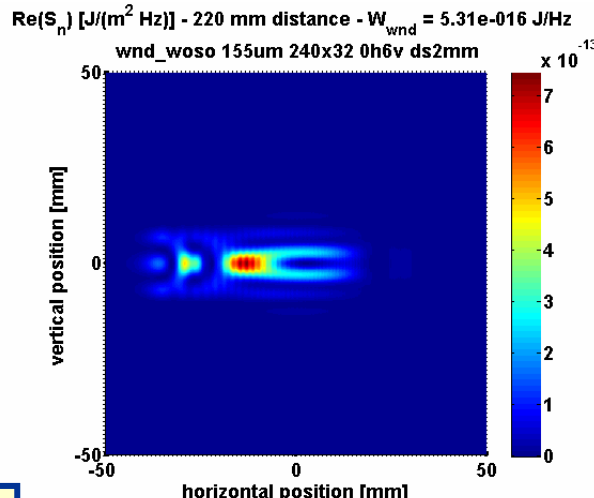
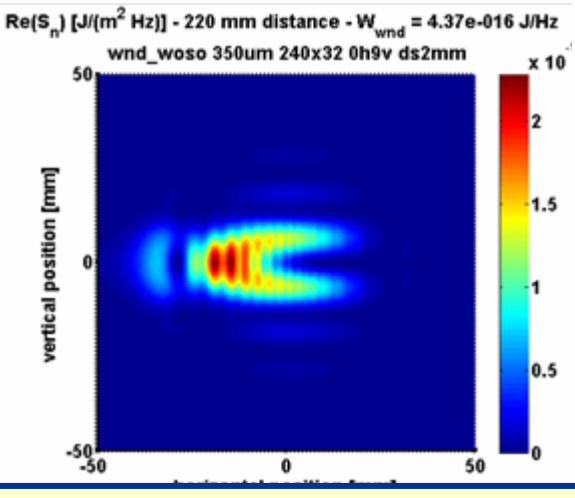
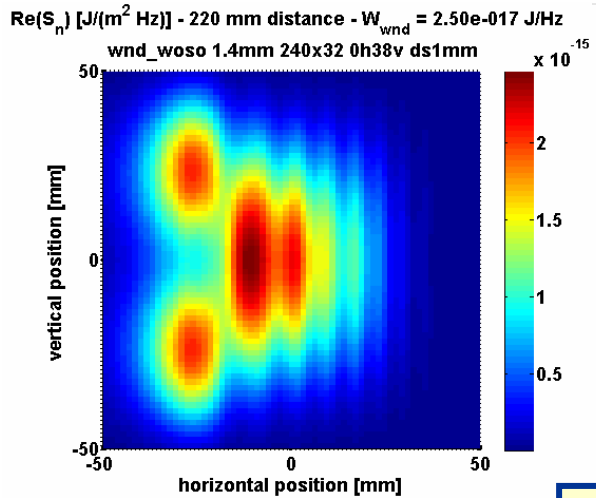
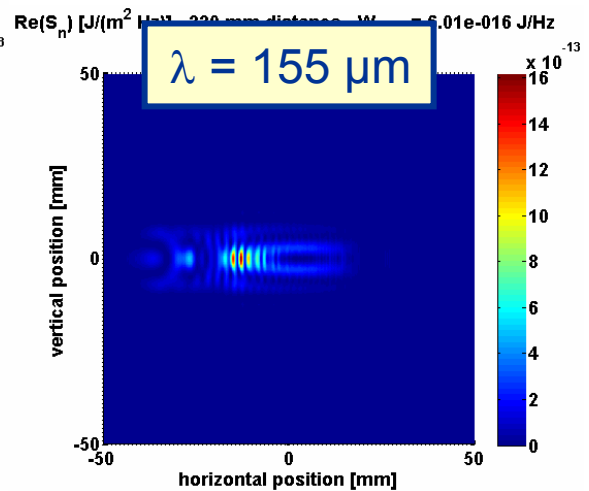
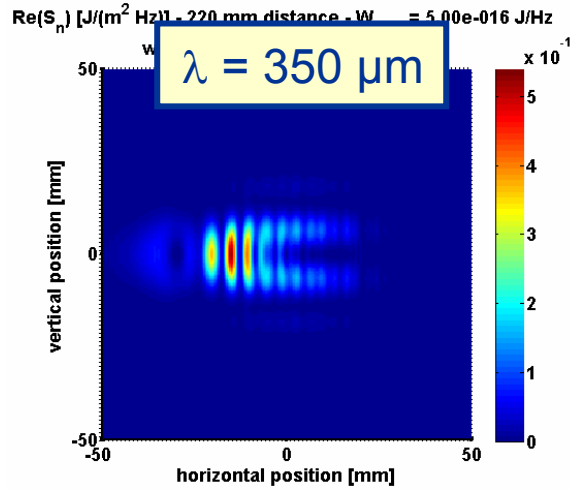
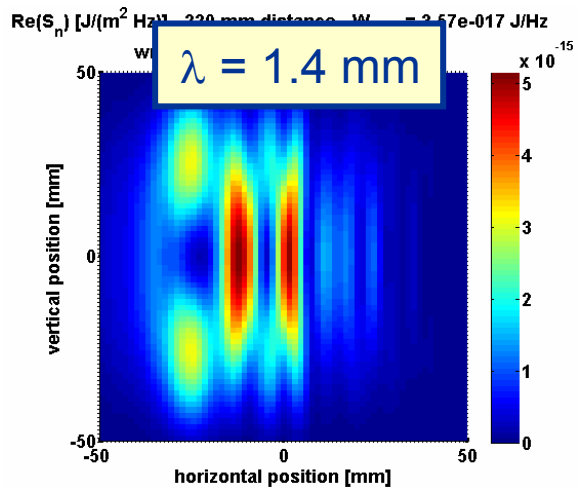
1.4mm signal overshadowed

# Influence of Side Walls on Intensity Patterns at 220mm for Measurement Frequencies

# Influence of Sidewalls @ 220mm



top/bottom + side walls

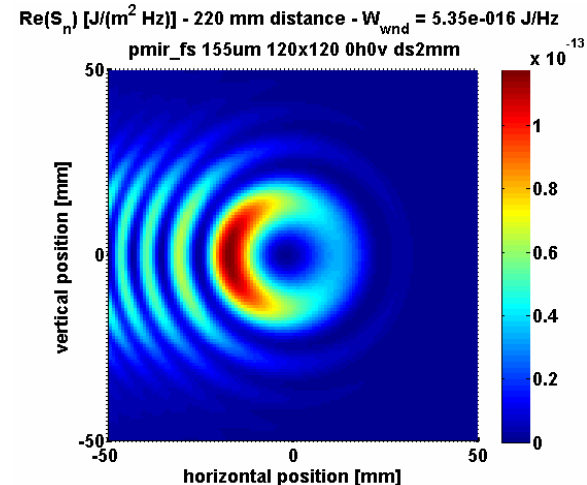
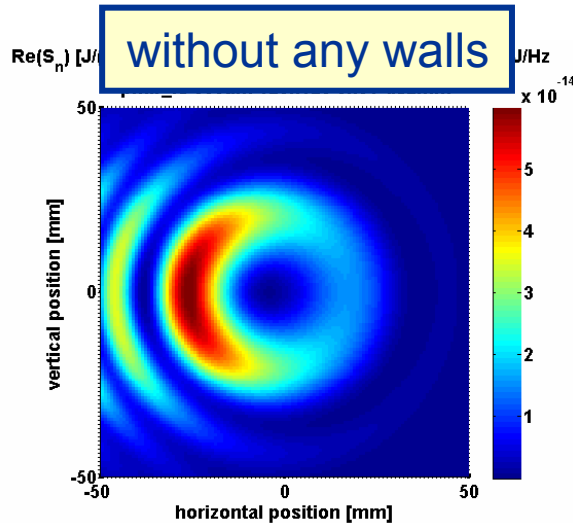
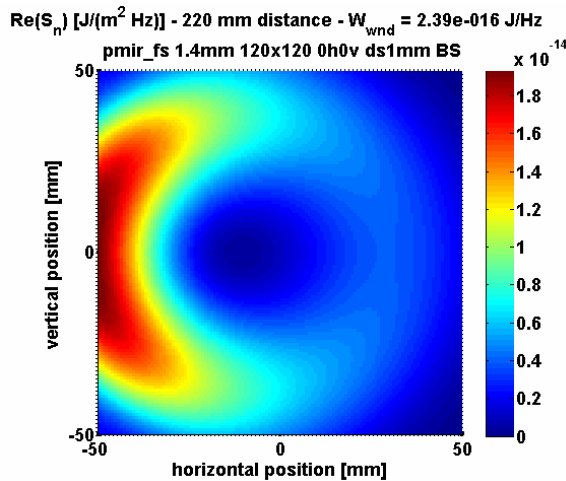
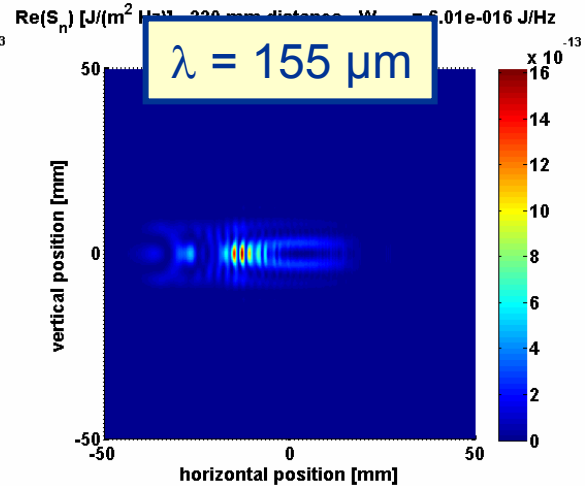
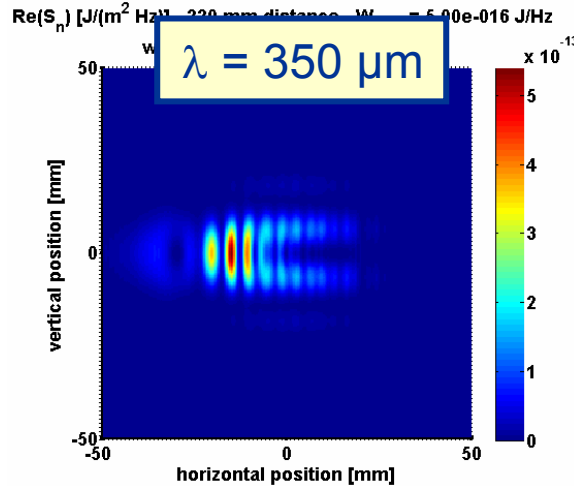
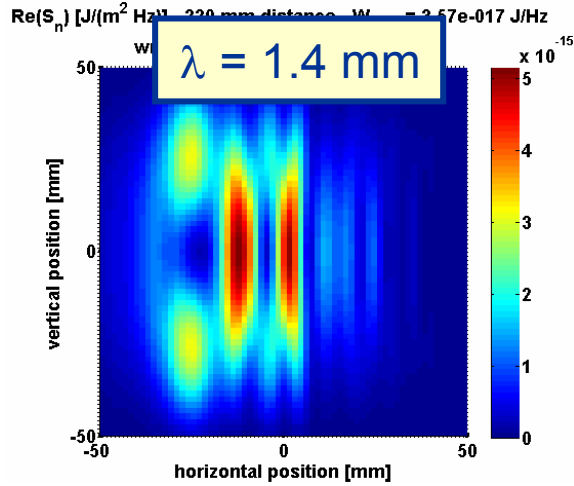


top/bottom walls + aperture

# Influence of Sidewalls @ 220mm



with top/bottom and side walls

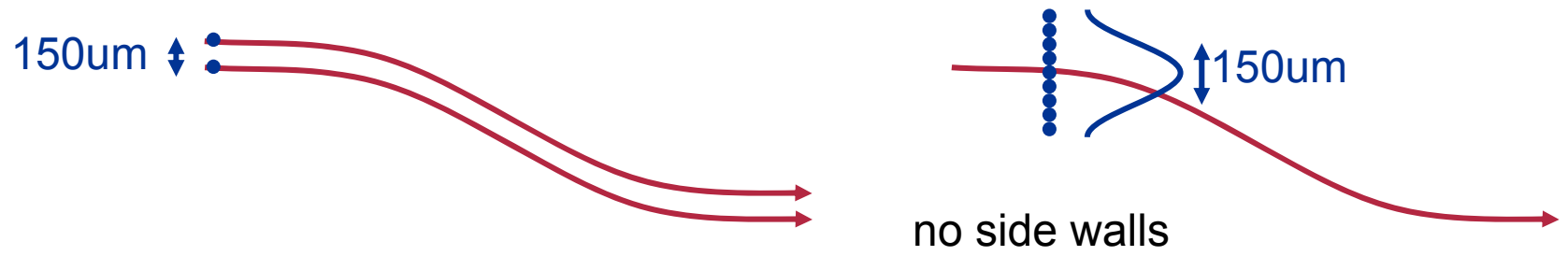




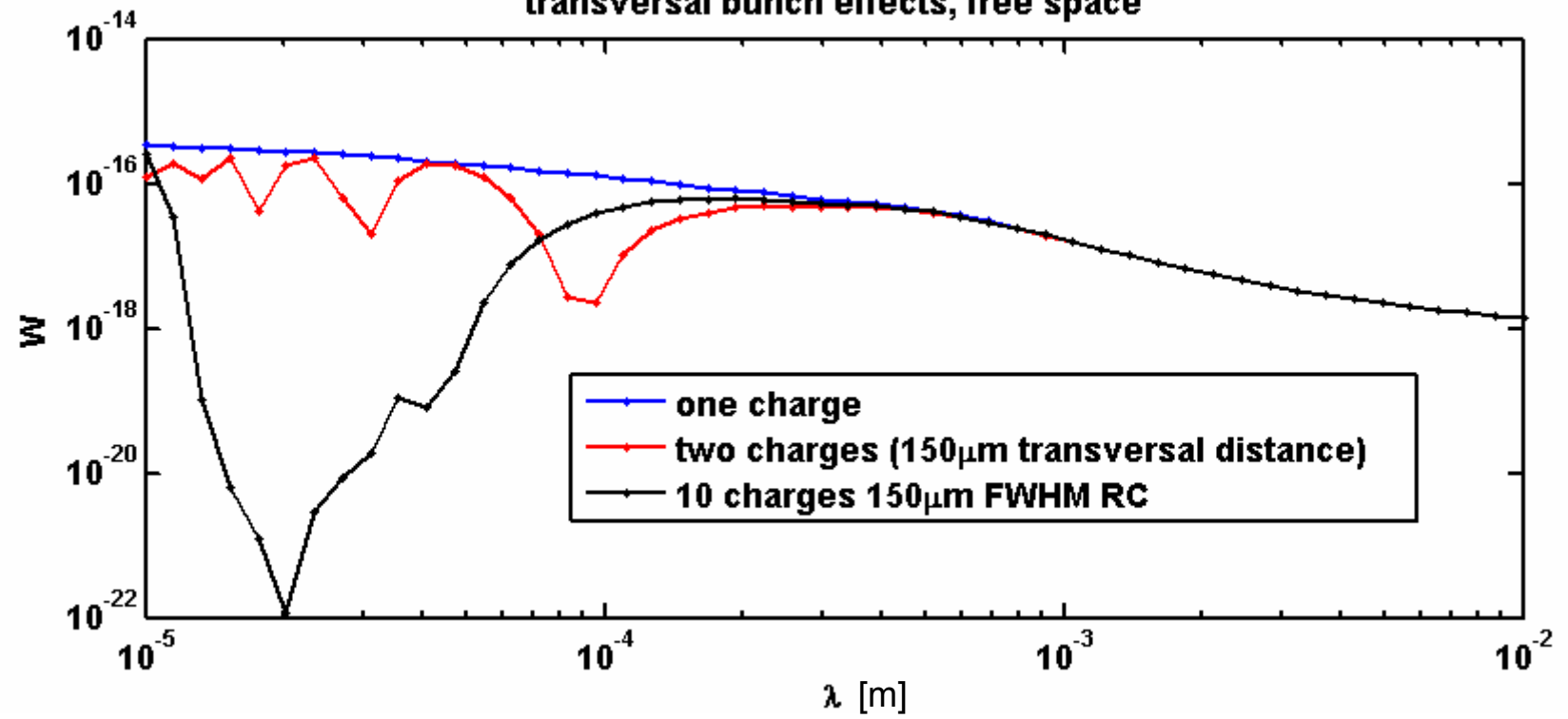
# Transversal Bunch Effects



compare single point charge to



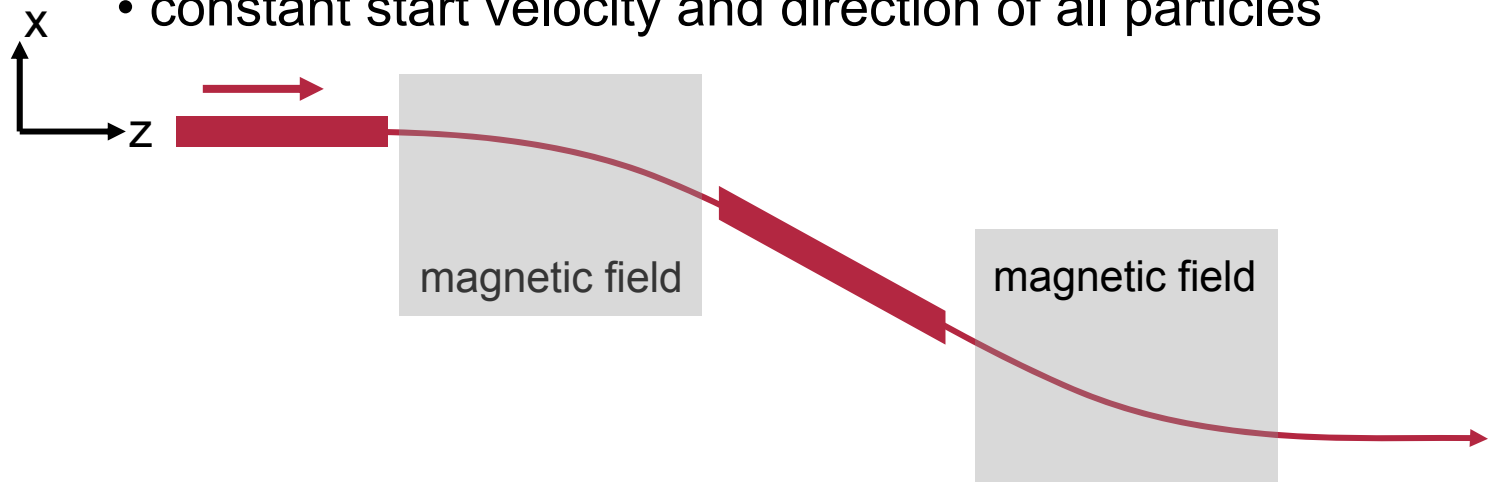
transversal bunch effects, free space



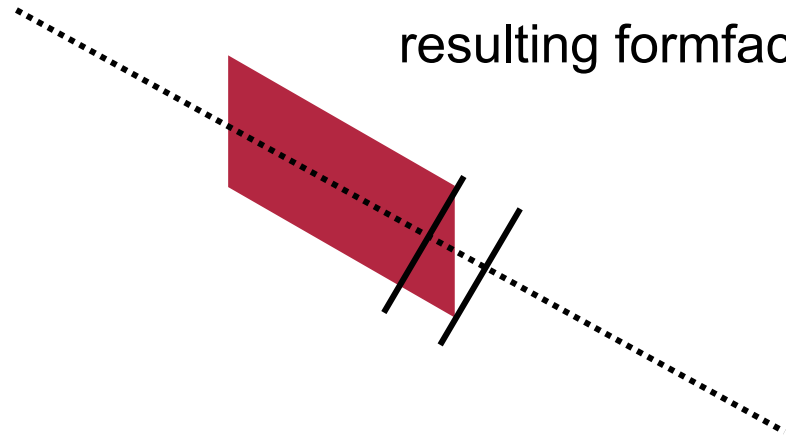


assumptions:

- charge distribution:  $f(x,z) = f_x(x) f_z(z)$
- constant start velocity and direction of all particles



resulting formfactor:  $F = F_z(\omega) F_x(\omega \sin(18^\circ))$



the shear causes mixing of transversal and longitudinal formfactor

consequences for practice?

# Conclusion

- influence of sidewalls on SR at first BC
- simulation by FIT and optics
- comparison with measurements
- influence of sidewalls seen
- transversal effects
- main open questions:
  - influence of sidewalls on bunch diagnostics?
  - influence of mirror focus and rest of beam line?
  - influence of transversal effects?